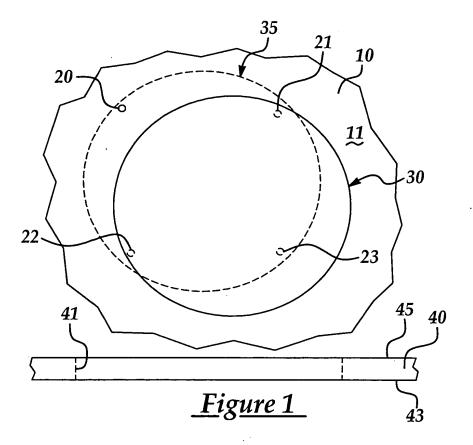


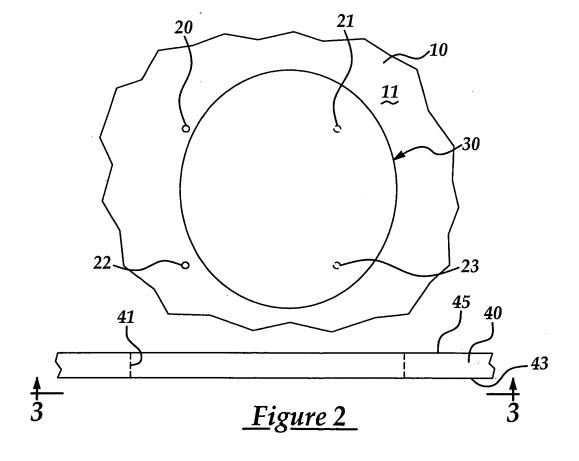
Inventor(s): Chen, et al Serial No.: To Be Assigned Filed: Herewith

Microchip Fabrication Chamber Wafer Detection

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Attorney Docket No.: 67,200-662







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For: Microchip Fabrication Chamber Wafer Detection Attorney Docket No.: 67,200-662

2/3 *30* <u>43</u> 31 41--11 -23 22 Figure 3 **51** 55 59 Figure 4 <u>Figure 5</u> 61_63 $\overline{c_1}$ C_2 DC

WAFER STATUS	P1	P2	P3	P4	FAULT
MISSING/BROKEN	0	0	0	0	1
MISPOSITIONED	0	X	X	X	1
MISPOSITIONED	X	0	X	X	1
MISPOSITIONED	X	X	0	X	1
MISPOSITIONED	X	X	X	0	1
PROPER	1	1	1	1	0

Figure 6

Figure 7



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For: Microchip Fabrication Chamber Wafer Detection

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WAFER STATUS	C1	C2	DC
BROKEN/MISSING	0	0	1
MISPOSITIONED	0	1	1
	1	0	1
PROPER	1	1	0

Figure 8

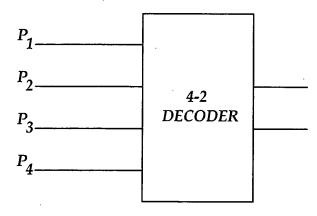


Figure 9

WAFER STATUS	P1	P2	P3	P4	FAULT
MISSING/BROKEN	0	0	0	0	1/1
MISPOSITIONED	0	0	X	X	1/0
(OFF 2 PINS)					
MISPOSITIONED	0	1	1	1	0/1
(OFF 1 PIN)					
MISPOSITIONED	X	0	0	X	1/0
(OFF 2 PINS)					
MISPOSITIONED	1	0	1	1	0/1
(OFF 1 PIN1)					
MISPOSITIONED	X	X	0	0	1/0
(OFF 2 PINS)					
MISPOSITIONED	1	1	0	1	0/1
(OFF 1 PIN)					
MISPOSITIONED	0	X	X	0	1/0
(OFF 2 PINS)					
MISPOSITIONED	1	1	1	0	0/1
(OFF 1 PIN)]
PROPER	1	1	1	1	0/0

<u>Figure 10</u>